

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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	Examiner	Art Unit	Page 1 of 1
	Cynthia Britt	2138	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,216,241 B1	04-2001	Fenstermaker et al.	714/718
	B	US-			
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	D	US-			
	E	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Realistic Fault Models and Test Procedure for Multi-port SRAMs" by Hamdioui et al. <input type="checkbox"/> IEEE International Workshop on Memory Technology, Design and Testing, Publication Date: 2001 On pages 65-72 INSPEC Accession Number: 7137971
	V	"A Built-in Self-testing Method for Embedded Multiport Memory Arrays" by Narayanan et al. Proceedings of the 21st IEEE Instrumentation and Measurement Technology Conference Publication Date: 18-20 May 2004 Vol 3, On pages 2027- 2032
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.